

<b>Notice of References Cited</b>	Application/Control No. 10/645,878	Applicant(s)/Patent Under Reexamination FUJII ET AL.	
	Examiner Shih-Chao Chen	Art Unit 2821	Page 1 of 1

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*	B	US-6,496,138	12-2002	Honma, Shinichi	342/70
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	M	US-			

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**NON-PATENT DOCUMENTS**

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